

| L Number | Hits   | Search Text   | DB  | Time stamp          |
|----------|--------|---|---|---------------------|
| 1        | 11504  | 250/306 or 250/307 or 250/310 or 250/311 or 250/442.11 or 250/397 or 250/396r   | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2004/06/17<br>16:45 |
| 2        | 514937 | @pd>=20040213   | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2004/06/17<br>16:45 |
| 3        | 337    | @ad>=20040213   | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2004/06/17<br>16:45 |
| 4        | 50     | ((electron adj microscope) or SEM or TEM) AND ((stereovision or stereoscopic or stereo-meter or parallax or stereoimage or stereo-image or (stereo near3 image\$3)) or ((three NEAR2 demension\$3) or three-demension\$3 or 3D or 3-D))) And ((beam or ebeam or e-beam) near2 (tilt\$5 or ang\$5) near2 (specimen or sample or object))   | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2004/06/17<br>16:50 |
| 5        | 50     | ((electron adj microscope) or SEM or TEM) AND ((stereovision or stereoscopic or stereo-meter or parallax or stereoimage or stereo-image or (stereo near3 image\$3)) or ((three NEAR2 demension\$3) or three-demension\$3 or 3D or 3-D))) And ((beam or ebeam or e-beam) near2 (tilt\$5 or ang\$5) near2 (specimen or sample or object)) And ((electron adj beam) or ebeam or e-beam) WITH (specimen or sample or object)) | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2004/06/17<br>16:50 |
| 6        | 32     | (Measur\$6 WITH template) and (((electron adj microscope) or SEM or TEM) AND ((stereovision or stereoscopic or stereo-meter or parallax or stereoimage or stereo-image or (stereo near3 image\$3)) or ((three NEAR2 demension\$3) or three-demension\$3 or 3D or 3-D))))  | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2004/06/17<br>16:51 |
| 7        | 14550  | (Rectifying or correcting) WITH (parameters or measurement)   | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2004/06/17<br>16:54 |
| 8        | 526120 | (250/306 or 250/307 or 250/310 or 250/311 or 250/442.11 or 250/397 or 250/396r) or @pd>=20040213  | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2004/06/17<br>16:51 |
| 9        | 121    | ((Rectifying or correcting) WITH (parameters or measurement)) and (250/306 or 250/307 or 250/310 or 250/311 or 250/442.11 or 250/397 or 250/396r)   | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2004/06/17<br>16:51 |
| 10       | 6944   | (Rectifying or correcting) NEAR4 (parameters or measurement)  | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2004/06/17<br>16:54 |
| 11       | 55     | ((Rectifying or correcting) NEAR4 (parameters or measurement)) and (250/306 or 250/307 or 250/310 or 250/311 or 250/442.11 or 250/397 or 250/396r)  | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2004/06/17<br>16:54 |

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| 12 | 4319  | (Rectifying or correcting) NEAR2<br>(parameters or measurement)   | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2004/06/17<br>16:54 |
| 13 | 39    | ((Rectifying or correcting) NEAR2<br>(parameters or measurement)) and (250/306<br>or 250/307 or 250/310 or 250/311 or<br>250/442.11 or 250/397 or 250/396r)   | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2004/06/17<br>16:57 |
| 14 | 60042 | ((sample or specimen or substrate or<br>relative or angle) NEAR2 tilt\$3)   | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2004/06/17<br>16:57 |
| 15 | 561   | ((sample or specimen or substrate or<br>relative or angle) NEAR2 tilt\$3)) and<br>(250/306 or 250/307 or 250/310 or 250/311<br>or 250/442.11 or 250/397 or 250/396r)  | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2004/06/17<br>16:57 |
| 16 | 3     | ((sample or specimen or substrate or<br>relative or angle) NEAR2 tilt\$3)) and<br>(250/306 or 250/307 or 250/310 or 250/311<br>or 250/442.11 or 250/397 or 250/396r))<br>and ((Rectifying or correcting) NEAR2<br>(parameters or measurement)) and (250/306<br>or 250/307 or 250/310 or 250/311 or<br>250/442.11 or 250/397 or 250/396r))                     | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2004/06/17<br>16:57 |
| 17 | 5     | ((sample or specimen or substrate or<br>relative or angle) NEAR2 tilt\$3)) and<br>(250/306 or 250/307 or 250/310 or 250/311<br>or 250/442.11 or 250/397 or 250/396r))<br>and ((Rectifying or correcting) WITH<br>(parameters or measurement)) and (250/306<br>or 250/307 or 250/310 or 250/311 or<br>250/442.11 or 250/397 or 250/396r))                      | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2004/06/17<br>16:58 |
| 19 | 168   | ((electron adj microscope) or SEM or<br>TEM) AND (stereovision or stereoscopic or<br>stereo-meter or parallax or stereoimage<br>or stereo-image or (stereo near3<br>image\$3)) or ((three NEAR2 demension\$3)<br>or three-demension\$3 or 3D or 3-D)) And<br>((beam or ebeam or e-beam) near2 (tilt\$5<br>or ang\$5) near2 (specimen or sample or<br>object)) | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2004/06/17<br>17:23 |
| 18 | 5     | (Measur\$6 SAME template SAME reference)<br>and (((electron adj microscope) or SEM<br>or TEM) AND ((stereovision or<br>stereoscopic or stereo-meter or parallax<br>or stereoimage or stereo-image or (stereo<br>near3 image\$3)) or ((three NEAR2<br>demension\$3) or three-demension\$3 or 3D<br>or 3-D))))  | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2004/06/17<br>17:23 |

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| 20 | 81 | (((electron adj microscope) or SEM or TEM) AND ((stereovision or stereoscopic or stereo-meter or parallax or stereoimage or stereo-image or (stereo near3 image\$3)) or ((three NEAR2 demension\$3) or three-demension\$3 or 3D or 3-D))) And ((beam or ebeam or e-beam) near2 (tilt\$5 or ang\$5) near2 (specimen or sample or object))) or (((electron adj microscope) or SEM or TEM) AND ((stereovision or stereoscopic or stereo-meter or parallax or stereoimage or stereo-image or (stereo near3 image\$3)) or ((three NEAR2 demension\$3) or three-demension\$3 or 3D or 3-D))) And ((beam or ebeam or e-beam) near2 (tilt\$5 or ang\$5) near2 (specimen or sample or object)) And (((electron adj beam) or ebeam or e-beam) WITH (specimen or sample or object))) or ((Measur\$6 WITH template) and (((electron adj microscope) or SEM or TEM) AND ((stereovision or stereoscopic or stereo-meter or parallax or stereoimage or stereo-image or (stereo near3 image\$3)) or ((three NEAR2 demension\$3) or three-demension\$3 or 3D or 3-D))))  | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2004/06/17<br>17:24 |
| 21 | 30 | (((electron adj microscope) or SEM or TEM) AND ((stereovision or stereoscopic or stereo-meter or parallax or stereoimage or stereo-image or (stereo near3 image\$3)) or ((three NEAR2 demension\$3) or three-demension\$3 or 3D or 3-D))) And ((beam or ebeam or e-beam) near2 (tilt\$5 or ang\$5) near2 (specimen or sample or object))) or (((electron adj microscope) or SEM or TEM) AND ((stereovision or stereoscopic or stereo-meter or parallax or stereoimage or stereo-image or (stereo near3 image\$3)) or ((three NEAR2 demension\$3) or three-demension\$3 or 3D or 3-D))) And ((beam or ebeam or e-beam) near2 (tilt\$5 or ang\$5) near2 (specimen or sample or object)) And (((electron adj beam) or ebeam or e-beam) WITH (specimen or sample or object))) or ((Measur\$6 WITH template) and (((electron adj microscope) or SEM or TEM) AND ((stereovision or stereoscopic or stereo-meter or parallax or stereoimage or stereo-image or (stereo near3 image\$3)) or ((three NEAR2 demension\$3) or three-demension\$3 or 3D or 3-D)))) and ((250/306 or 250/307 or 250/310 or 250/311 or 250/442.11 or 250/397 or 250/396r) or @pd>=20040213) | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2004/06/17<br>17:24 |
| 22 | 30 | (((electron adj microscope) or SEM or TEM) AND (stereovision or stereoscopic or stereo-meter or parallax or stereoimage or stereo-image or (stereo near3 image\$3)) or ((three NEAR2 demension\$3) or three-demension\$3 or 3D or 3-D)) And ((beam or ebeam or e-beam) near2 (tilt\$5 or ang\$5) near2 (specimen or sample or object))) and ((250/306 or 250/307 or 250/310 or 250/311 or 250/442.11 or 250/397 or 250/396r) or @pd>=20040213)  | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2004/06/17<br>17:24 |

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| 24 | 35 | ((((electron adj microscope) or SEM or TEM) AND (stereovision or stereoscopic or stereo-meter or parallax or stereoimage or stereo-image or (stereo near3 image\$3)) or ((three NEAR2 demension\$3) or three-demension\$3 or 3D or 3-D)) And ((beam or ebeam or e-beam) near2 (tilt\$5 or ang\$5) near2 (specimen or sample or object))) and ((250/306 or 250/307 or 250/310 or 250/311 or 250/442.11 or 250/397 or 250/396r) or @pd>=20040213)) or (((((electron adj microscope) or SEM or TEM) AND ((stereovision or stereoscopic or stereo-meter or parallax or stereoimage or stereo-image or (stereo near3 image\$3)) or ((three NEAR2 demension\$3) or three-demension\$3 or 3D or 3-D))) And ((beam or ebeam or e-beam) near2 (tilt\$5 or ang\$5) near2 (specimen or sample or object))) or (((electron adj microscope) or SEM or TEM) AND ((stereovision or stereoscopic or stereo-meter or parallax or stereoimage or stereo-image or (stereo near3 image\$3)) or ((three NEAR2 demension\$3) or three-demension\$3 or 3D or 3-D)))) and ((250/306 or 250/307 or 250/310 or 250/311 or 250/442.11 or 250/397 or 250/396r) or @pd>=20040213)) | USPAT;<br>US-PGPUB;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | 2004/06/17<br>17:25 |
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